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INFORMATION DISCLOSURE CITATION

Atty. Docket No.	06720.0074	Appln. No.	09/987,616
Applicant	Ming-Duo KER et al.		
Filing Date	November 15, 2001	Group:	2836

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Examiner Initial*		Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
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Examiner	Boris Benenson	Date Considered	7.31.03

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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